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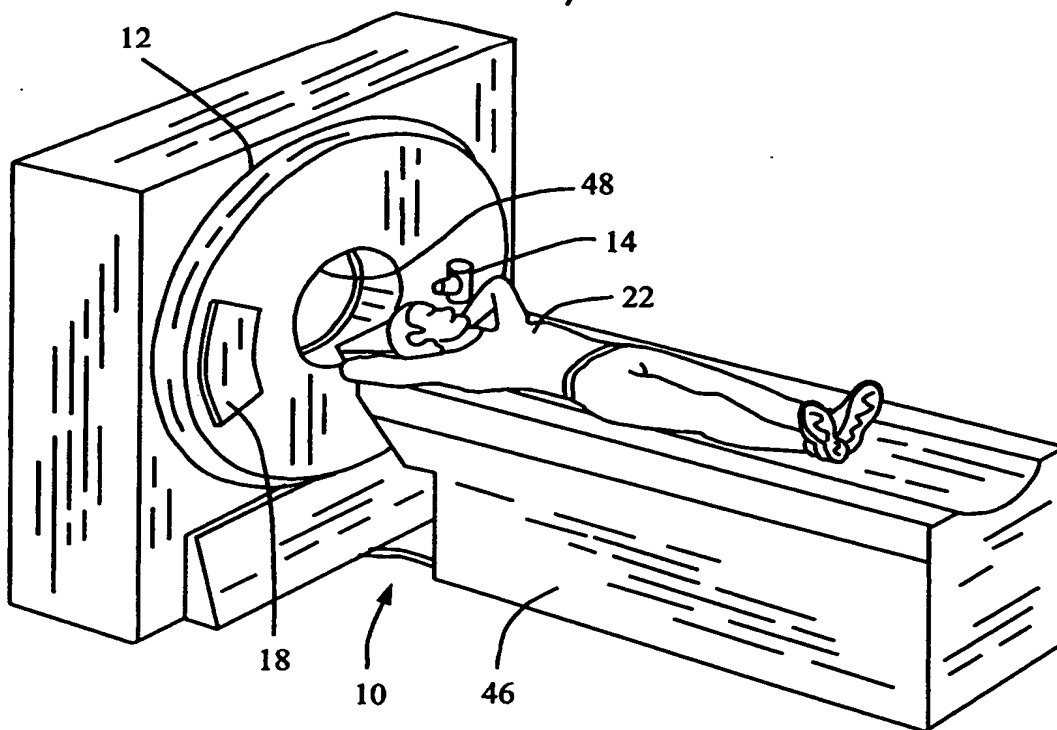


FIG. 1

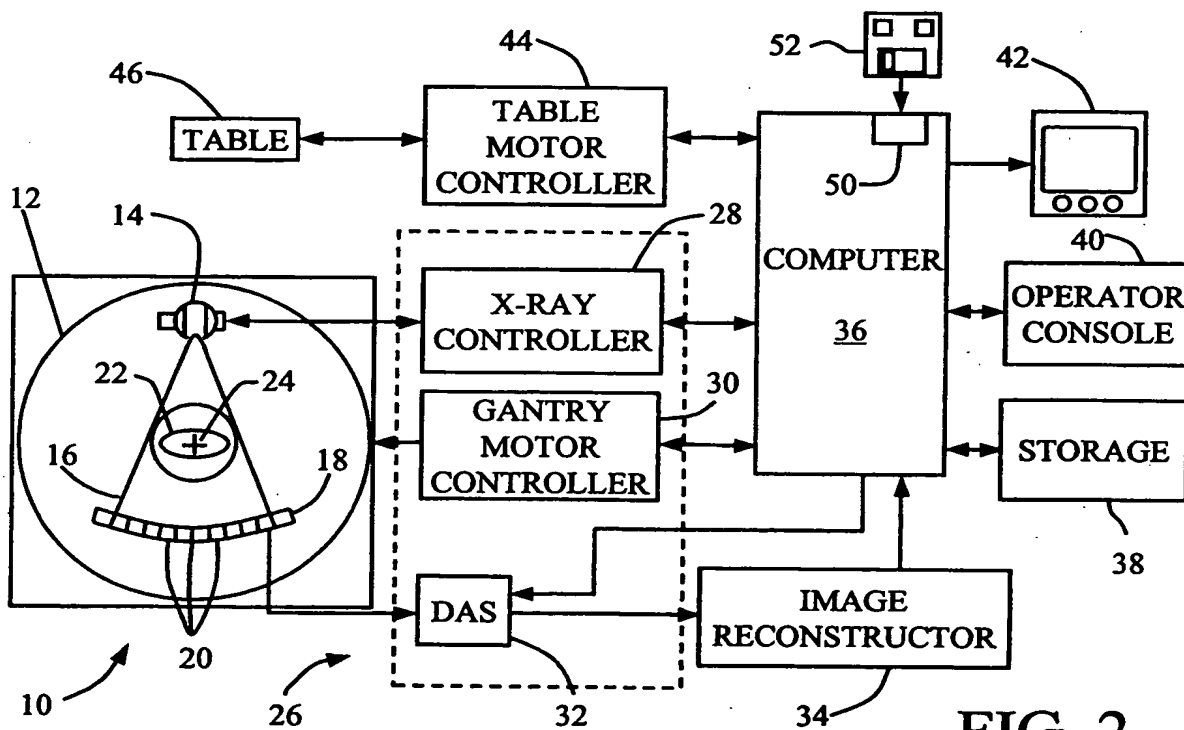


FIG. 2

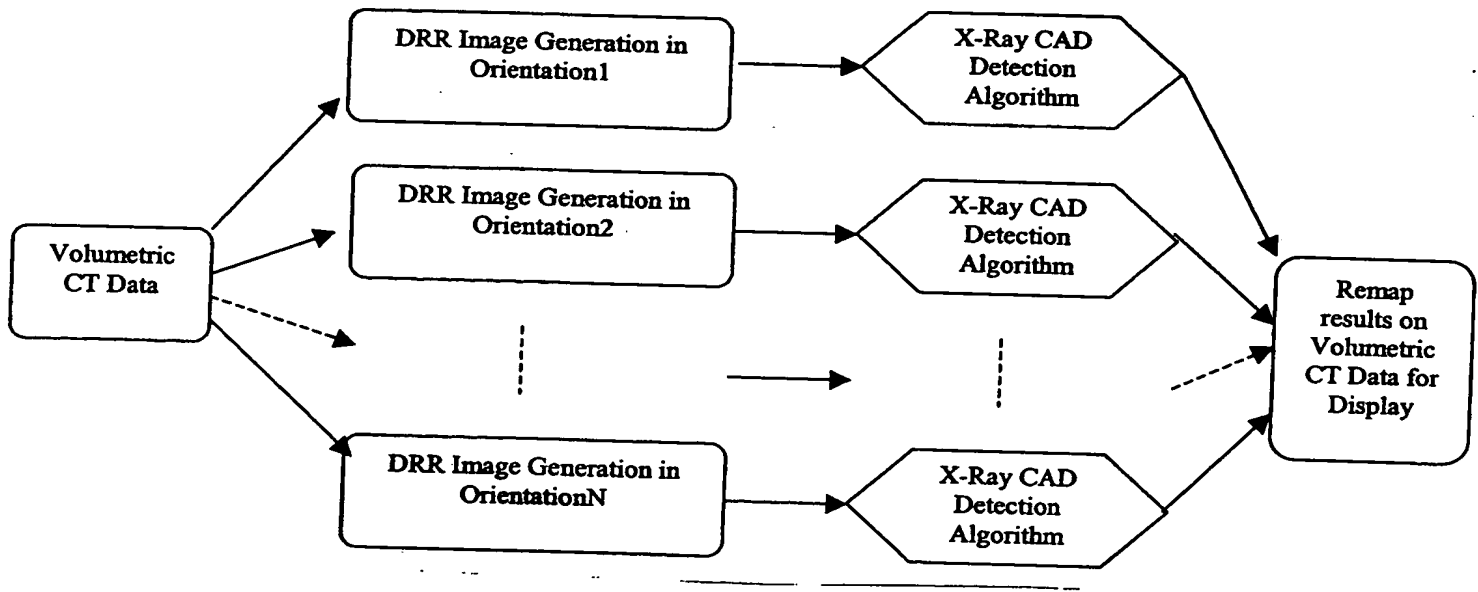
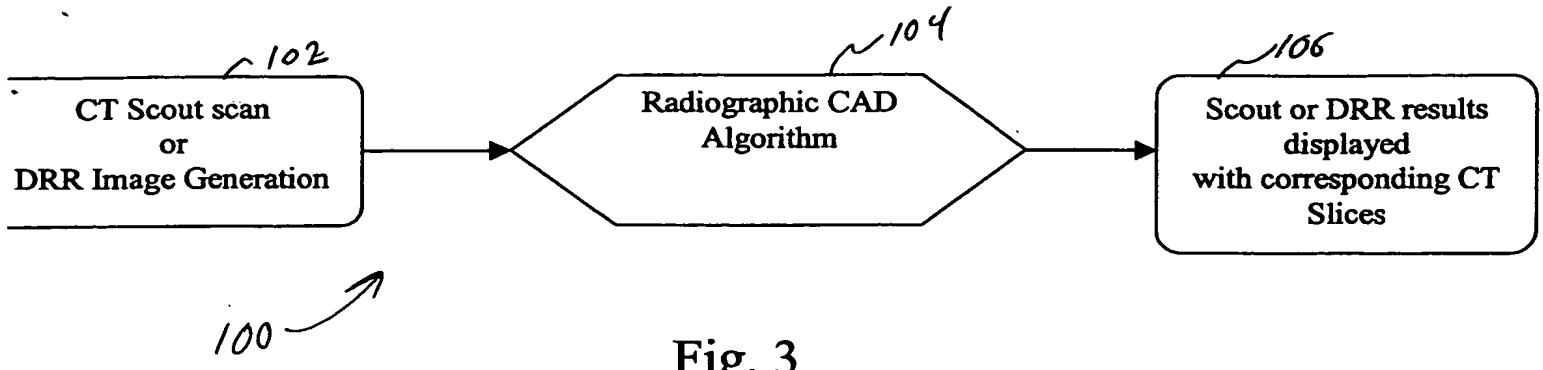


Fig 4

3/7

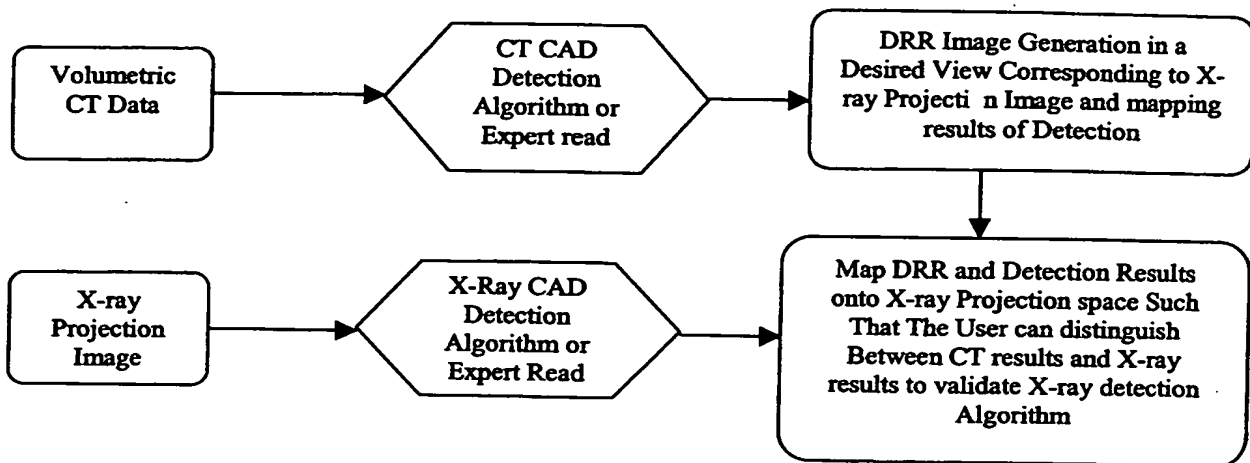


Fig 5

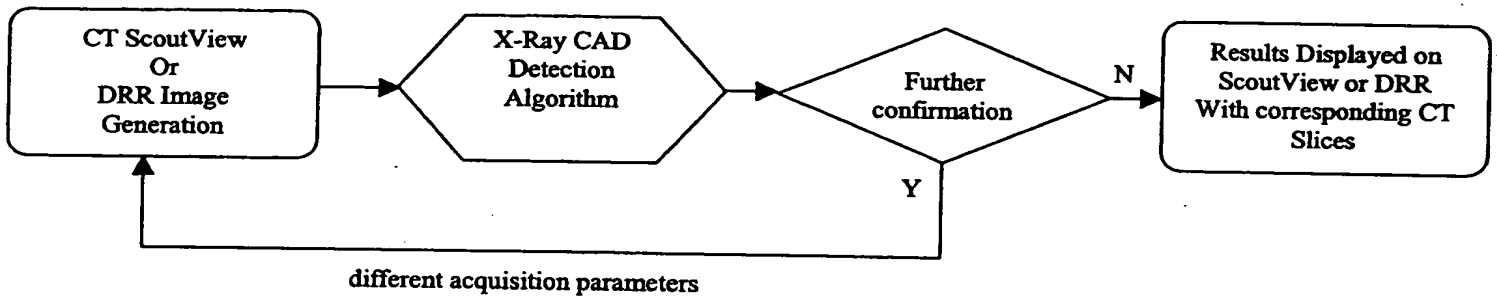


Fig. 6

4/7

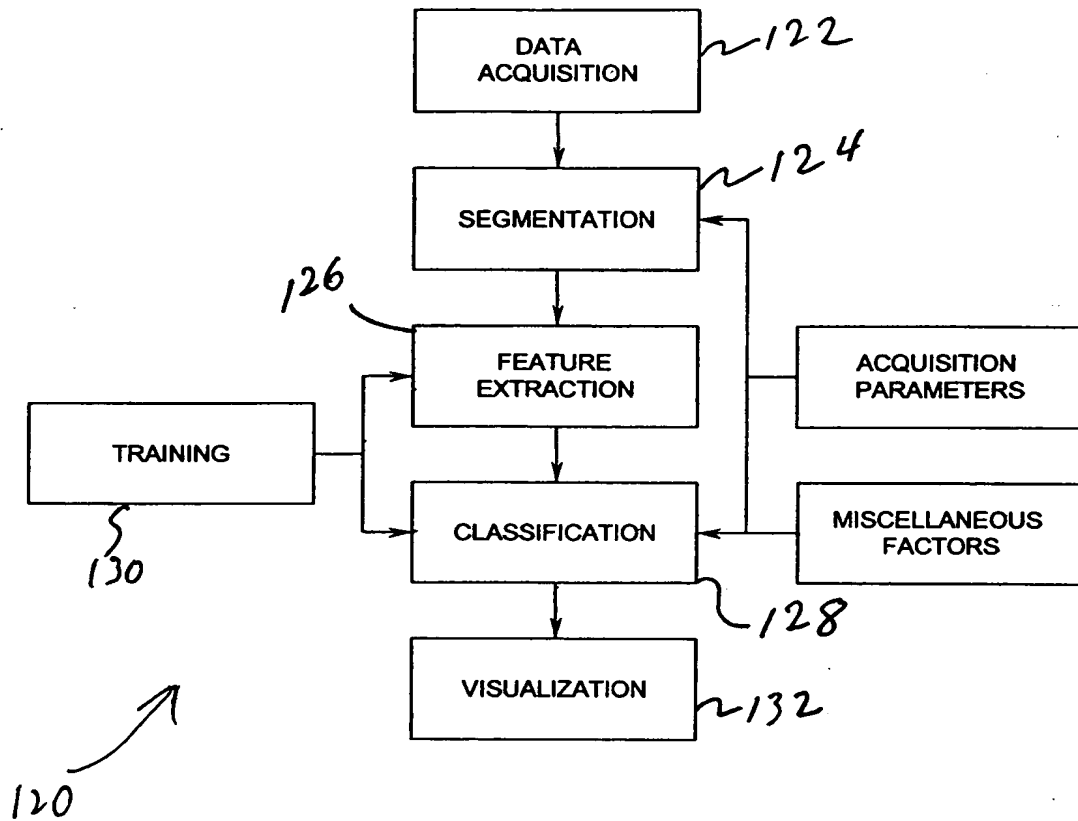
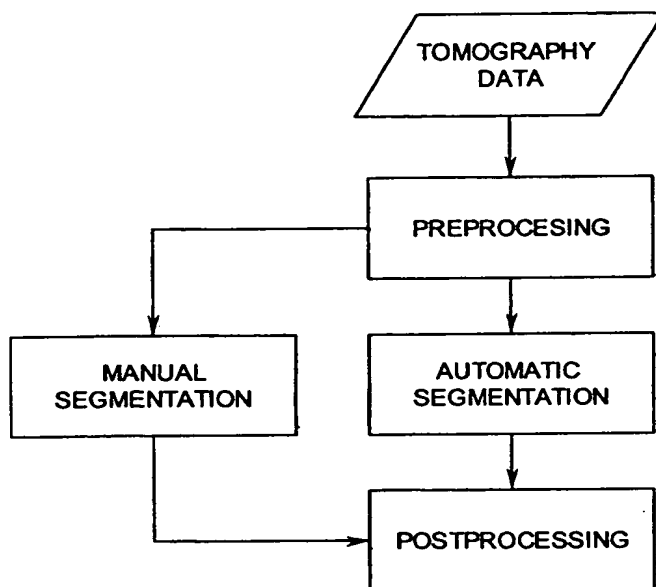


Figure 7. Schematic of CAD process

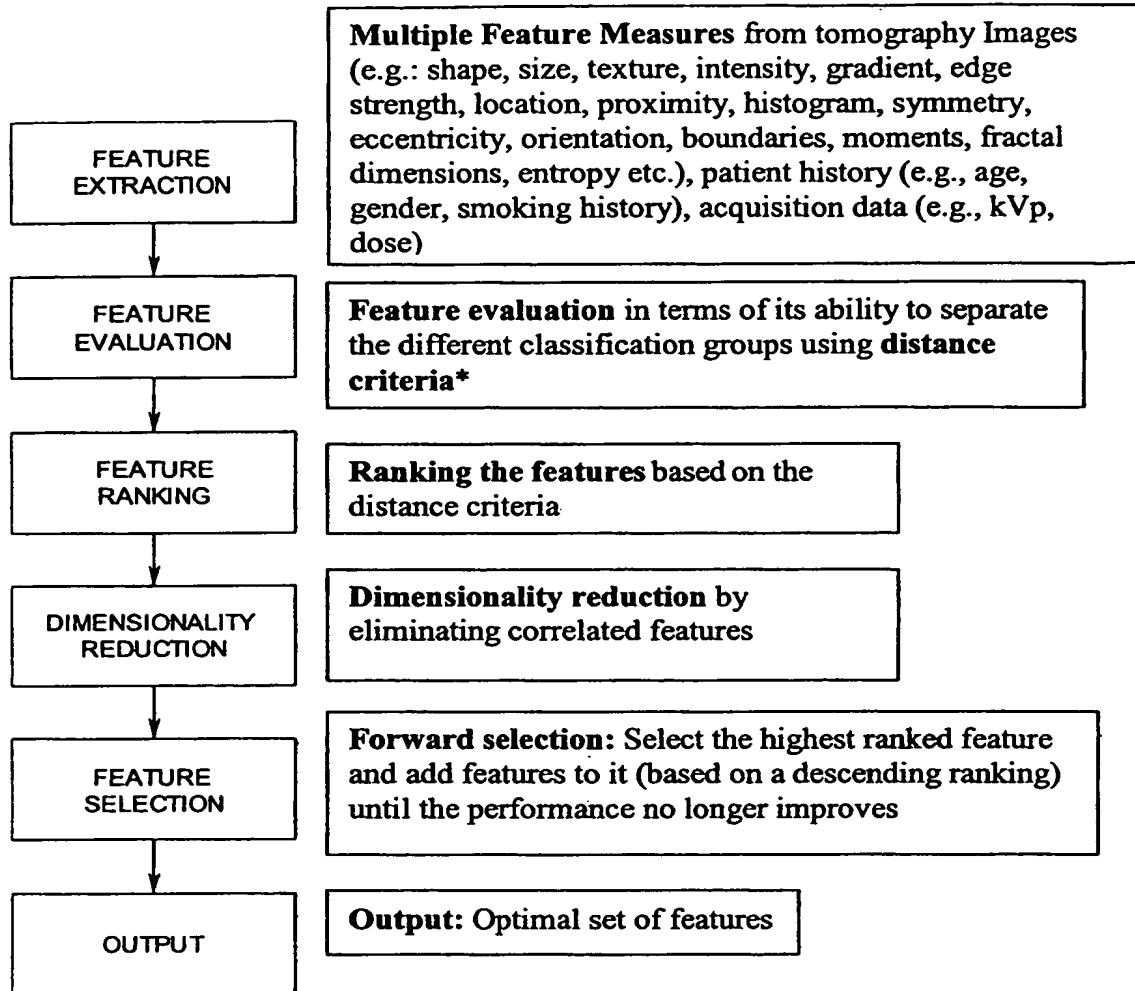
5/7



124 ↗

Figure 8. Segmentation process for data.

6/7

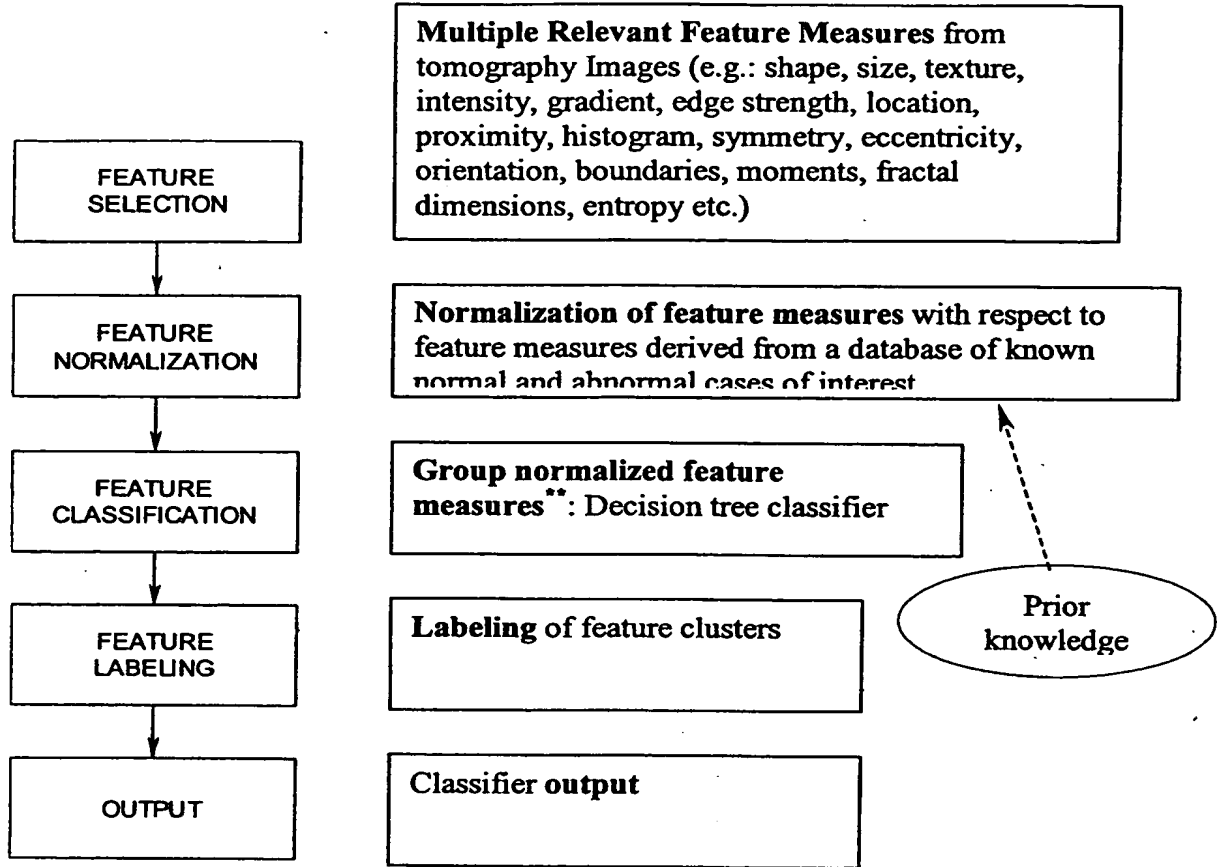


126 ↗

Figure 9. Feature selection process for data.

\* Several different distance criteria can be used: Divergence, Bhattacharya distance, Mahalanobis distance. These techniques are described in standard textbooks including: K. Fukunaga, Introduction to Statistical Pattern Recognition. Academic Press, 2nd ed., 1990.

7/7



**Figure 10. Feature classification process for tomographic data.**

**\*\* Several different methods can be used: Decision tree analysis, discriminant function analysis, Bayes' minimum-risk method, clustering techniques, similarity measure approach. These techniques are described in standard textbooks including: Fundamentals of digital image processing by Anil K. Jain, Prentice Hall (1988).**